Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/070,074	HEISE ET AL.	
Examiner	Art Unit	
Phung T Nguyen	2632	

	SEAR	CHED	
Class	Subclass	Date	Examiner
340	438	6/2/2005	PTN
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345	173	>	-
	349	6/2/2005	PTN

INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
340	461	6/2/2005	PTN		
	933	V	V		
345	173	6/2/2005	PTN		

SEARCH NOTES (INCLUDING SEARCH STRATEGY)					
	DATE	EXMR			
EAST	4/6/2004	PTN			
EAST	6/2/2005	PTN			
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